Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/625,909	STURA ET AL.	
Examiner	Art Unit	
Justin Y. Lee	2617	

SEARCHED					
Class	Subclass	Date	Examiner		
455	405, 406	1/8/2007	JL		

INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
East	1/8/2007	JL	
Duc Nguyen	1/8/2007	JL	
e.			